# XP04112

## Silicon PNP epitaxial planar type

### For digital circuits

#### ■ Features

- Two elements incorporated into one package (Transistors with built-in resistor)
- Reduction of the mounting area and assembly cost by one half

#### ■ Basic Part Number

• UNR2112 × 2

#### ■ Absolute Maximum Ratings $T_a = 25^{\circ}C$

| Parameter                             | Symbol           | Rating      | Unit |  |
|---------------------------------------|------------------|-------------|------|--|
| Collector-base voltage (Emitter open) | $V_{CBO}$        | -50         | V    |  |
| Collector-emitter voltage (Base open) | V <sub>CEO</sub> | -50         | V    |  |
| Collector current                     | $I_{C}$          | -100        | mA   |  |
| Total power dissipation               | $P_{T}$          | 150         | mW   |  |
| Junction temperature                  | T <sub>j</sub>   | 150         | °C . |  |
| Storage temperature                   | T <sub>stg</sub> | -55 to +150 | °C   |  |

#### Package

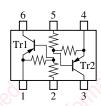
• Code

SMini6-G1
• Pin Name

1: Emitter (Tr1) 4: Emitter (Tr2) 2: Base (Tr1) 5: Base (Tr2) 3: Collector (Tr2) 6: Collector (Tr1)

#### ■ Marking Symbol: 6R

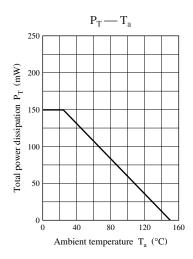
#### ■ Internal Connection

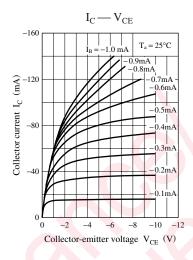


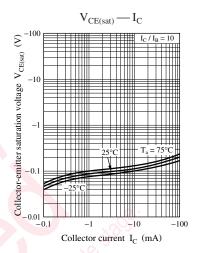
### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

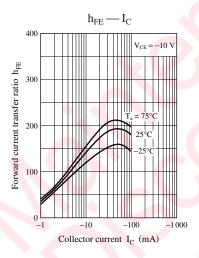
| Parameter                                    | Symbol               | Conditions   | Min  | Тур | Max    | Unit |
|--|----------------------|--|------|-----|--------|------|
| Collector-base voltage (Emitter open)        | $V_{CBO}$            | $I_C = -10 \mu\text{A}, I_E = 0$                                       | -50  |     |        | V    |
| Collector-emitter voltage (Base open)        | V <sub>CEO</sub>     | $I_{\rm C} = -2 \text{ mA}, I_{\rm B} = 0$                             | -50  |     |        | V    |
| Collector-base cutoff current (Emitter open) | $I_{CBO}$            | $V_{CB} = -50 \text{ V}, I_E = 0$                                      |      |     | - 0.1  | μΑ   |
| Collector-emitter cutoff current (Base open) | I <sub>CEO</sub>     | $V_{CE} = -50 \text{ V}, I_{B} = 0$                                    |      |     | - 0.5  | μΑ   |
| Emitter-base cutoff current (Collector open) | I <sub>EBO</sub>     | $V_{EB} = -6 \text{ V}, I_C = 0$                                       |      |     | - 0.2  | mA   |
| Forward current transfer ratio               | $h_{FE}$             | $V_{CE} = -10 \text{ V}, I_{C} = -5 \text{ mA}$                        | 60   |     |        | _    |
| Collector-emitter saturation voltage         | V <sub>CE(sat)</sub> | $I_C = -10 \text{ mA}, I_B = -0.3 \text{ mA}$                          |      |     | - 0.25 | V    |
| Output voltage high-level                    | V <sub>OH</sub>      | $V_{CC} = -5 \text{ V}, V_B = -0.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | -4.9 |     |        | V    |
| Output voltage low-level                     | V <sub>OL</sub>      | $V_{CC} = -5 \text{ V}, V_B = -2.5 \text{ V}, R_L = 1 \text{ k}\Omega$ |      |     | - 0.2  | V    |
| Input resistance                             | R <sub>1</sub>       |  | -30% | 22  | +30%   | kΩ   |
| Resistance ratio                             | $R_1 / R_2$          |  | 0.8  | 1.0 | 1.2    | _    |
| Transition frequency                         | $f_T$                | $V_{CB} = -10 \text{ V}, I_E = 1 \text{ mA}, f = 200 \text{ MHz}$      |      | 80  |        | MHz  |

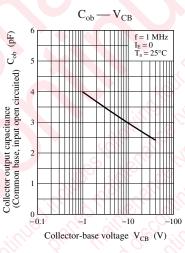
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

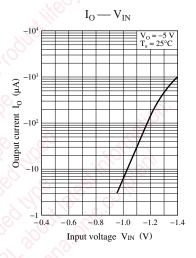


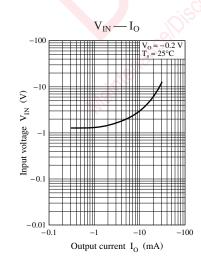






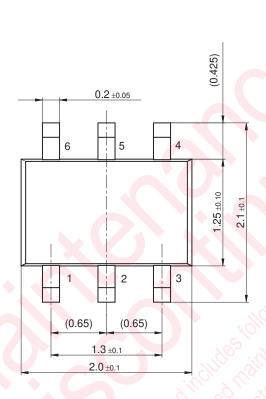


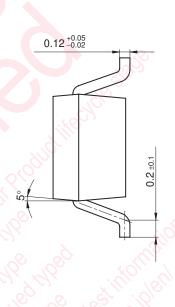


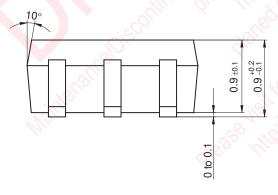


2 SJJ00162CED

SMini6-G1 Unit: mm







SJJ00162CED 3

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